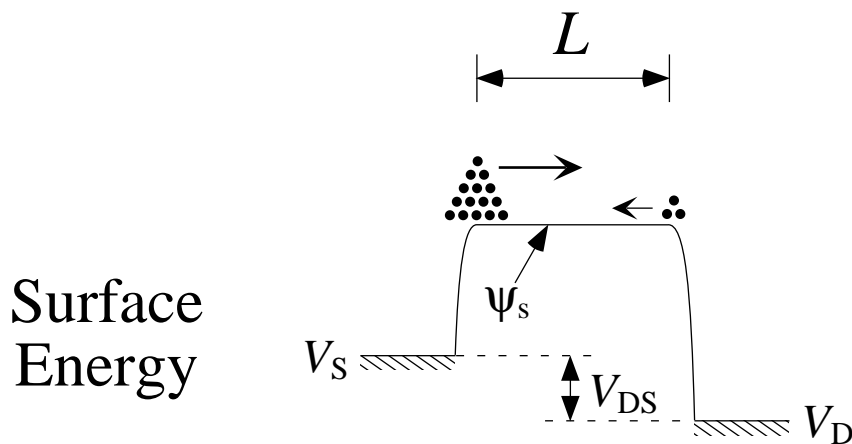
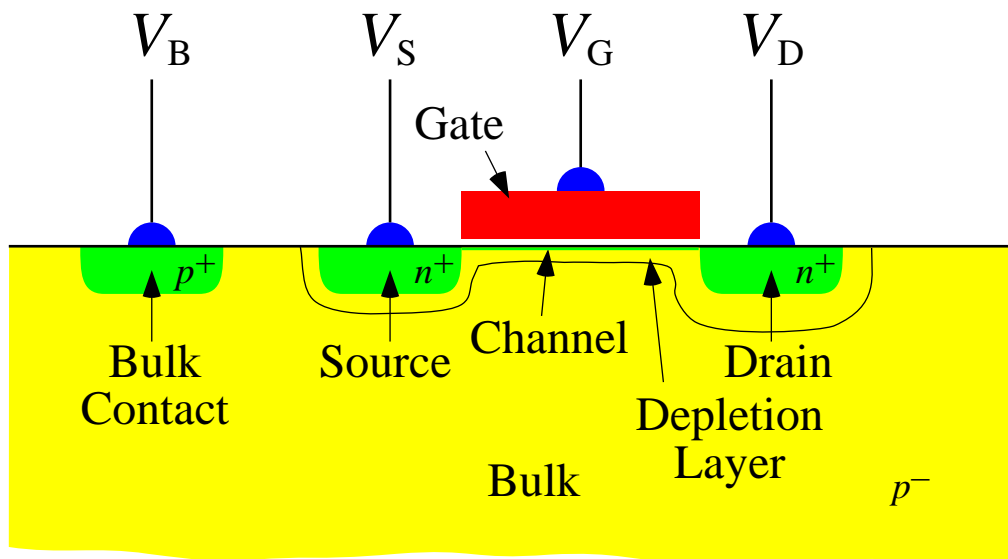
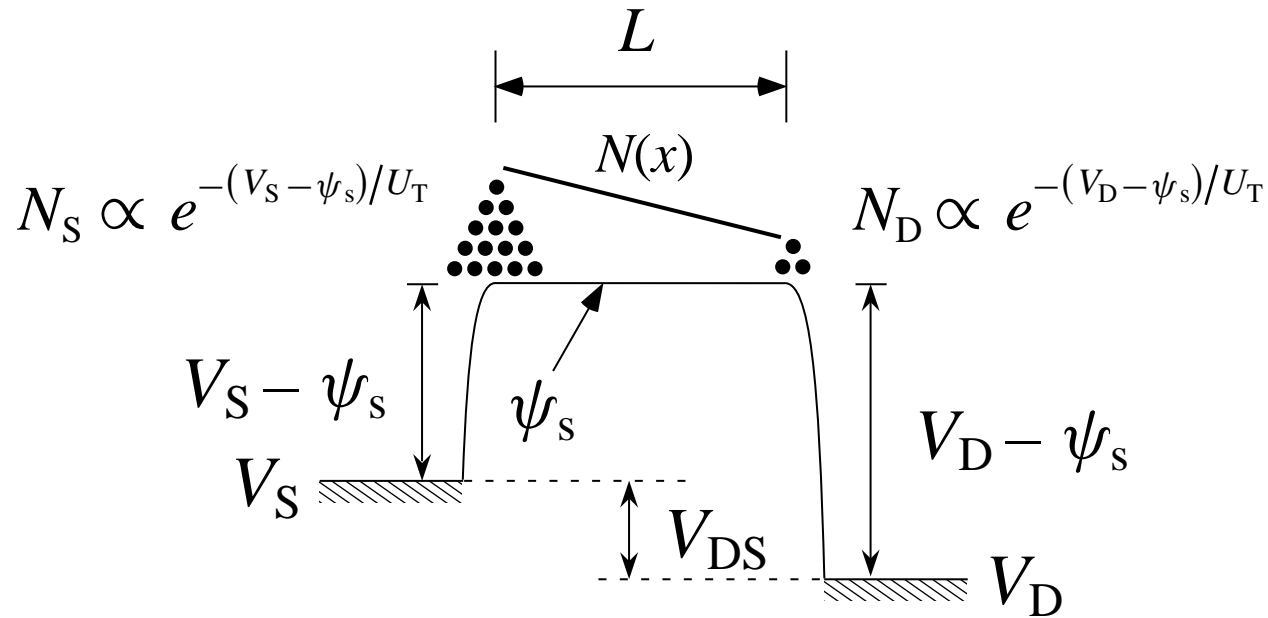


Surface Energy in Subthreshold



Subthreshold Channel Current



► Current flow is by **diffusion**:

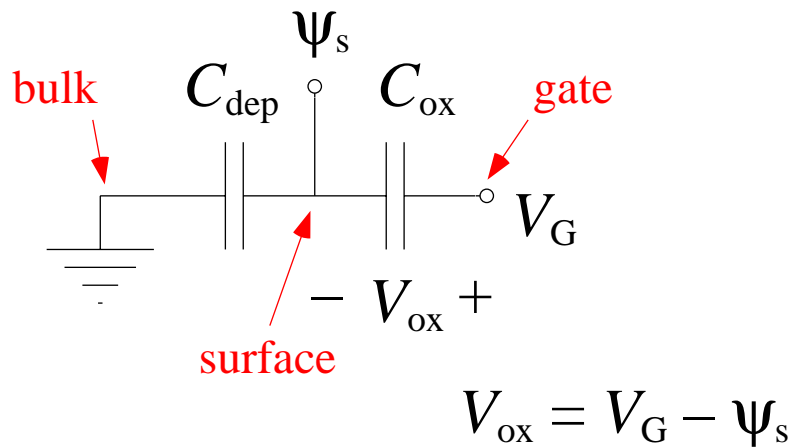
$$I = -WqD \frac{\partial N}{\partial x} = -WqD \frac{N_D - N_S}{L} = WqD \frac{N_S - N_D}{L}$$

$$= \frac{W}{L} qDN_0 \left(e^{-(V_S - \psi_s)/U_T} - e^{-(V_D - \psi_s)/U_T} \right)$$

$$\psi_s \approx \psi_0 + \kappa V_G$$

$$I = \frac{W}{L} I_0 e^{\kappa V_G / U_T} \left(e^{-V_S / U_T} - e^{-V_D / U_T} \right)$$

Capacitive-Divider View of κ



► Conservation of charge:

$$\Delta Q_s = 0 = \frac{\partial Q_s}{\partial \psi_s} \Delta \psi_s - \frac{\partial Q_s}{\partial V_{\text{ox}}} \Delta V_{\text{ox}}$$

\uparrow
 C_{dep}
 \uparrow
 C_{ox}

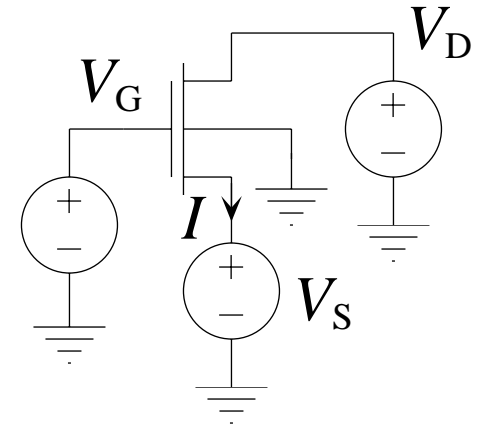
$$(C_{\text{ox}} + C_{\text{dep}}) \Delta \psi_s = C_{\text{ox}} \Delta V_G$$

$$\frac{\partial \psi_s}{\partial V_G} \approx \frac{\Delta \psi_s}{\Delta V_G} = \frac{C_{\text{ox}}}{C_{\text{ox}} + C_{\text{dep}}} = \kappa$$

Subthreshold Channel Current

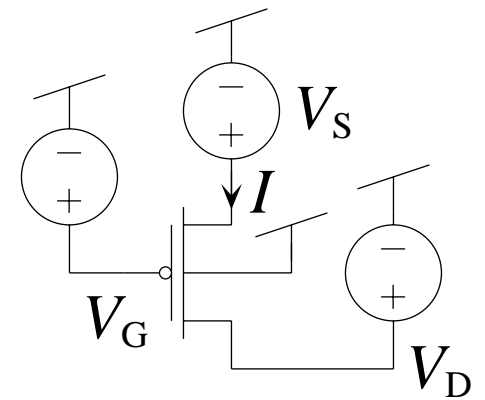
► nMOS:

$$\begin{aligned}
 I &= \frac{W}{L} I_0 e^{\kappa V_G / U_T} \left(e^{-V_S / U_T} - e^{-V_D / U_T} \right) \\
 &= \frac{W}{L} I_0 e^{(\kappa V_G - V_S) / U_T} \left(1 - e^{-V_{DS} / U_T} \right) \\
 &\approx \frac{W}{L} I_0 e^{(\kappa V_G - V_S) / U_T} \quad (\text{for } V_{DS} \geq 4 U_T)
 \end{aligned}$$



► pMOS:

$$\begin{aligned}
 I &= \frac{W}{L} I_0 e^{-\kappa V_G / U_T} \left(e^{V_S / U_T} - e^{V_D / U_T} \right) \\
 &= \frac{W}{L} I_0 e^{(V_S - \kappa V_G) / U_T} \left(1 - e^{V_{DS} / U_T} \right) \\
 &\approx \frac{W}{L} I_0 e^{(V_S - \kappa V_G) / U_T} \quad (\text{for } V_{DS} \leq -4 U_T)
 \end{aligned}$$

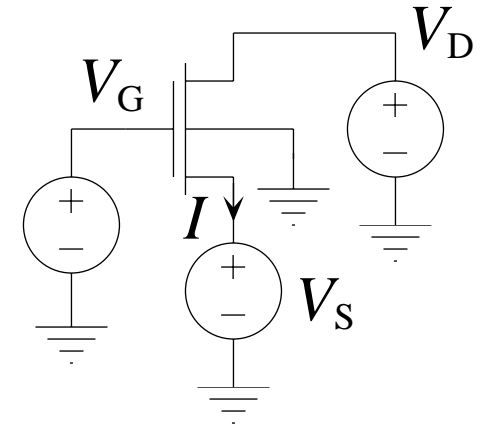


** Note here that $V_G < 0$, $V_S < 0$, and $V_D < 0$.

Subthreshold Channel Current

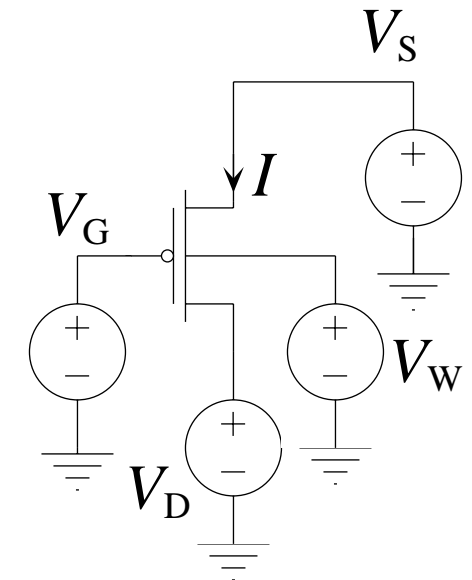
► nMOS:

$$\begin{aligned}
 I &= \frac{W}{L} I_0 e^{\kappa V_G / U_T} \left(e^{-V_S / U_T} - e^{-V_D / U_T} \right) \\
 &= \frac{W}{L} I_0 e^{(\kappa V_G - V_S) / U_T} \left(1 - e^{-V_{DS} / U_T} \right) \\
 &\approx \frac{W}{L} I_0 e^{(\kappa V_G - V_S) / U_T} \quad (\text{for } V_{DS} \geq 4 U_T)
 \end{aligned}$$



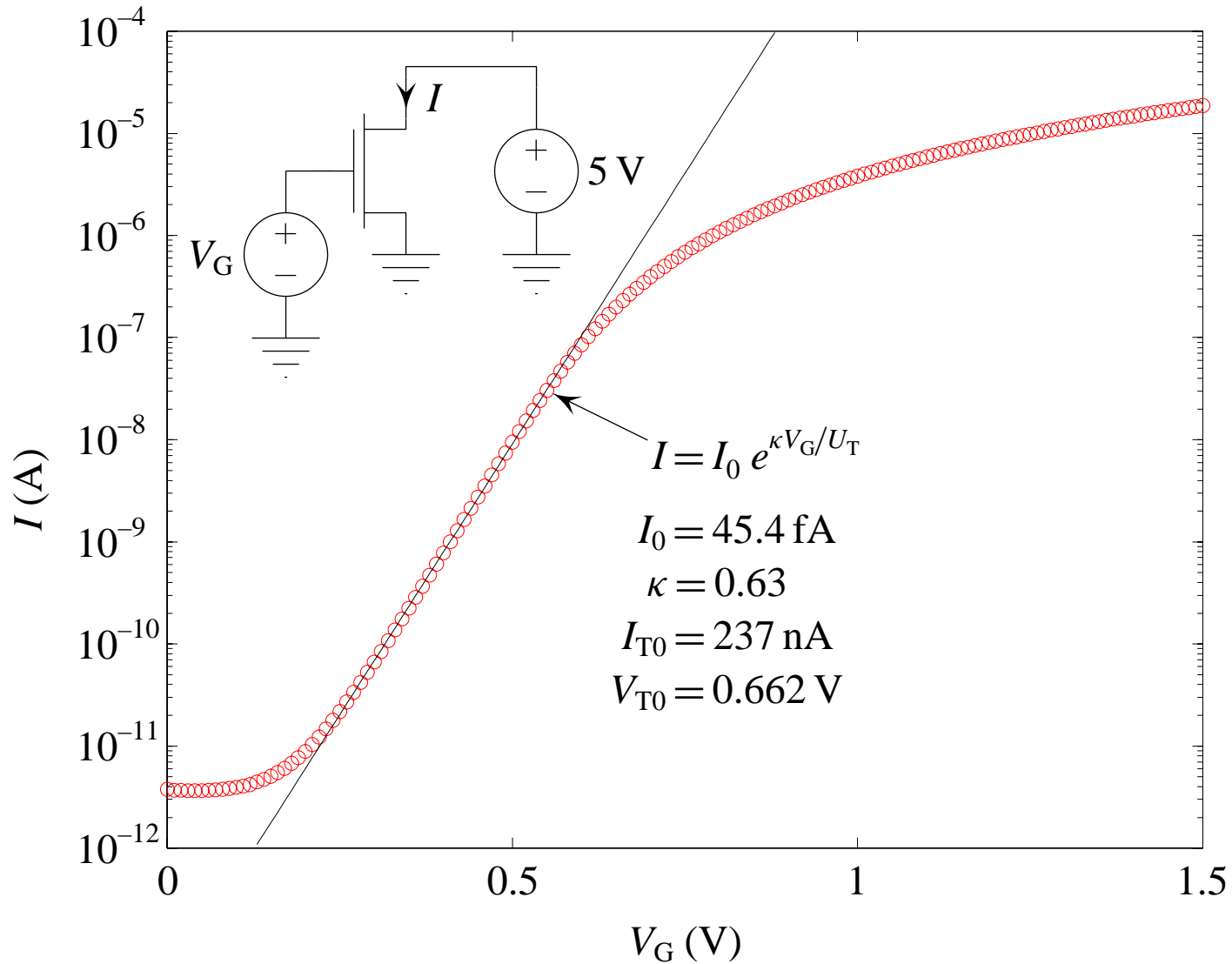
► pMOS:

$$\begin{aligned}
 I &= \frac{W}{L} I_0 e^{\kappa(V_W - V_G) / U_T} \left(e^{-(V_W - V_S) / U_T} - e^{-(V_W - V_D) / U_T} \right) \\
 &= \frac{W}{L} I_0 e^{(V_S - (1 - \kappa)V_W - \kappa V_G) / U_T} \left(1 - e^{V_{DS} / U_T} \right) \\
 &\approx \frac{W}{L} I_0 e^{(V_S - (1 - \kappa)V_W - \kappa V_G) / U_T} \quad (\text{for } V_{DS} \leq -4 U_T)
 \end{aligned}$$

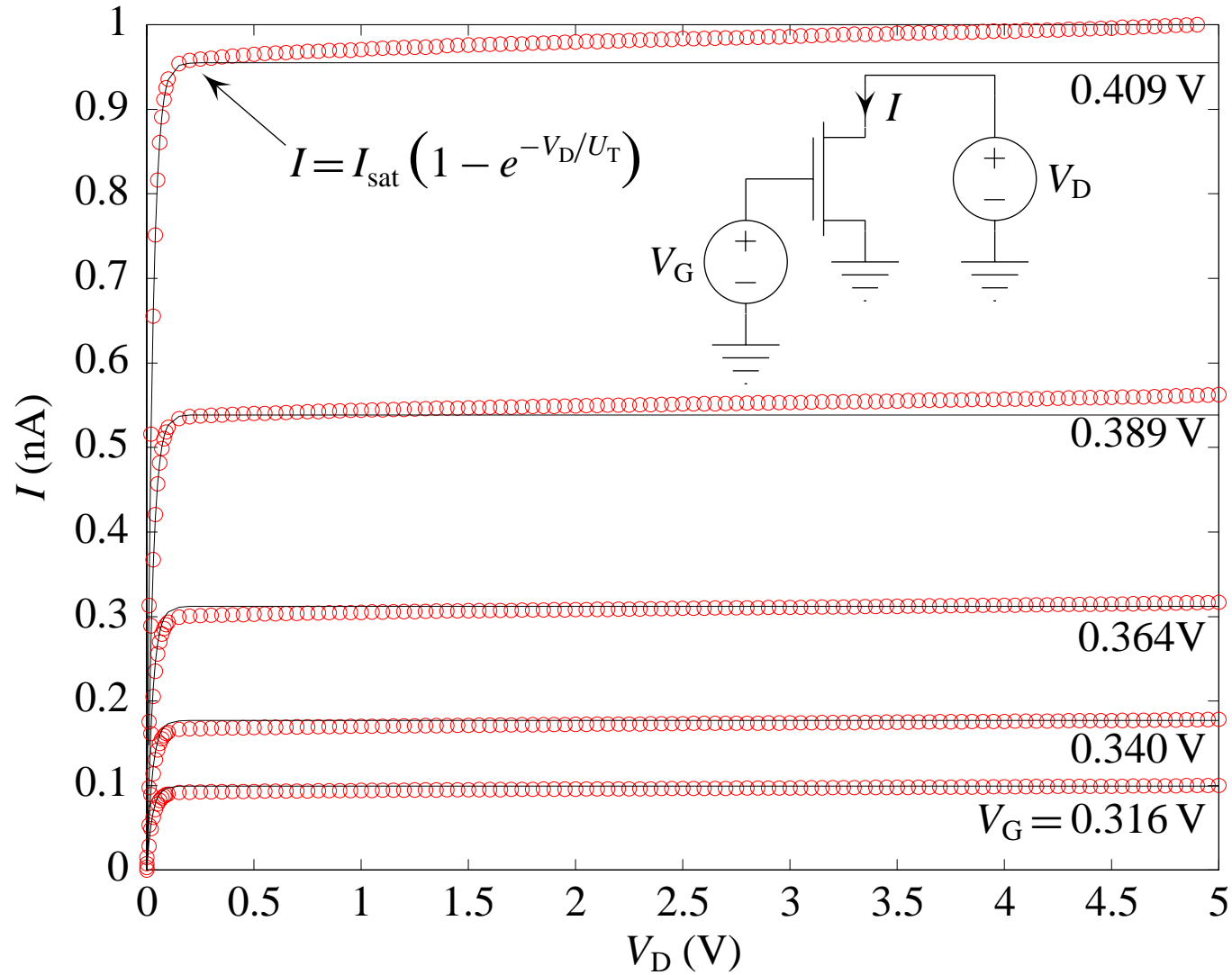


** Note here that $V_G > 0$, $V_S > 0$, $V_D > 0$, and $V_W > 0$.

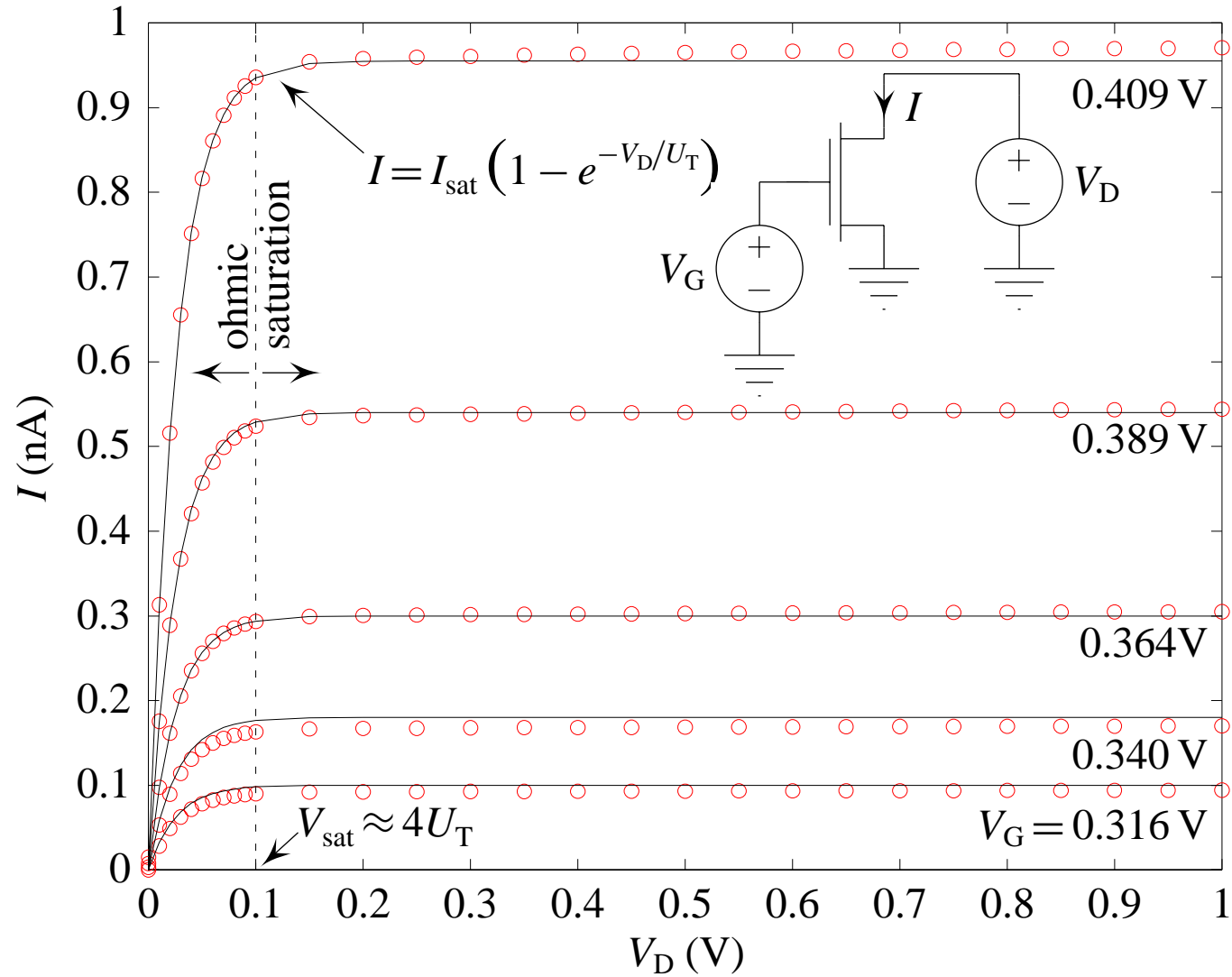
Subthreshold Channel Current in Saturation



Subthreshold Drain Characteristics



Subthreshold Drain Characteristics

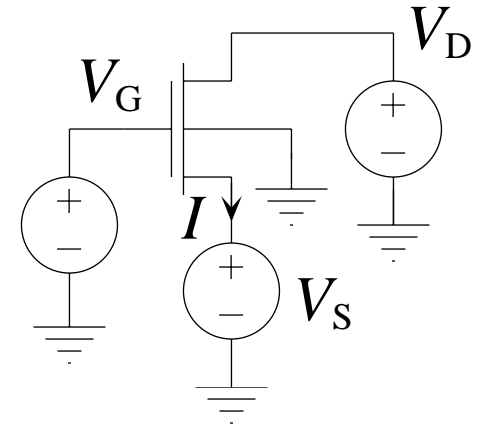


Above-Threshold Channel Current

► *n*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} \left[\left(\kappa(V_G - V_{T0}) - V_S \right)^2 - \left(\kappa(V_G - V_{T0}) - V_D \right)^2 \right]$$

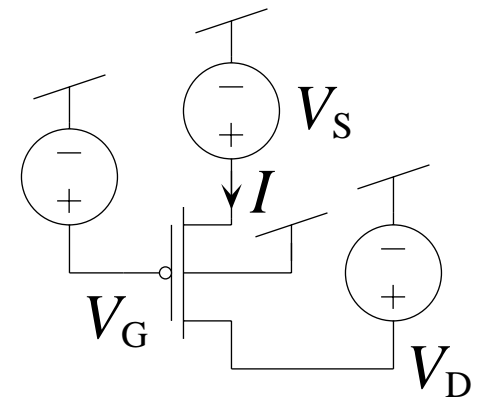
$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} \left(\kappa(V_G - V_{T0}) - V_S \right)^2, \text{ for } V_D \geq \kappa(V_G - V_{T0})$$



► *p*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} \left[\left(V_S - \kappa(V_G - V_{T0}) \right)^2 - \left(V_D - \kappa(V_G - V_{T0}) \right)^2 \right]$$

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} \left(V_S - \kappa(V_G - V_{T0}) \right)^2, \text{ for } V_D \leq \kappa(V_G - V_{T0})$$



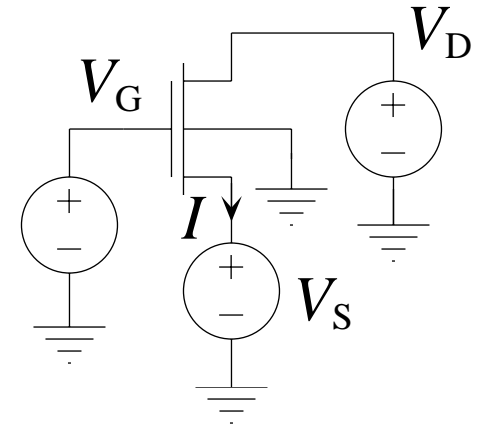
** Note here that $V_G < 0$, $V_S < 0$, $V_D < 0$, and $V_{T0} < 0$.

Above-Threshold Channel Current

► *n*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} \left[(\kappa(V_G - V_{T0}) - V_S)^2 - (\kappa(V_G - V_{T0}) - V_D)^2 \right]$$

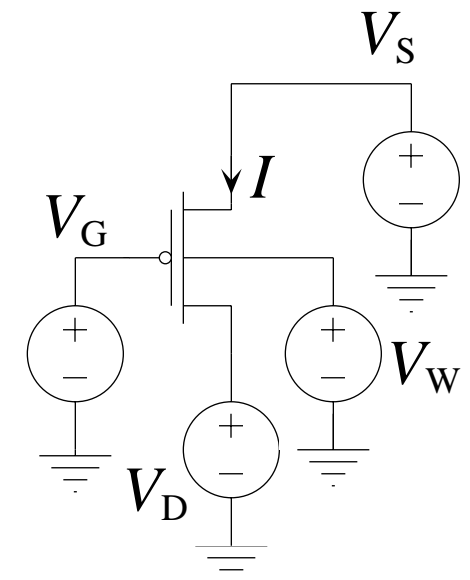
$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} (\kappa(V_G - V_{T0}) - V_S)^2, \text{ for } V_D \geq \kappa(V_G - V_{T0})$$



► *p*MOS:

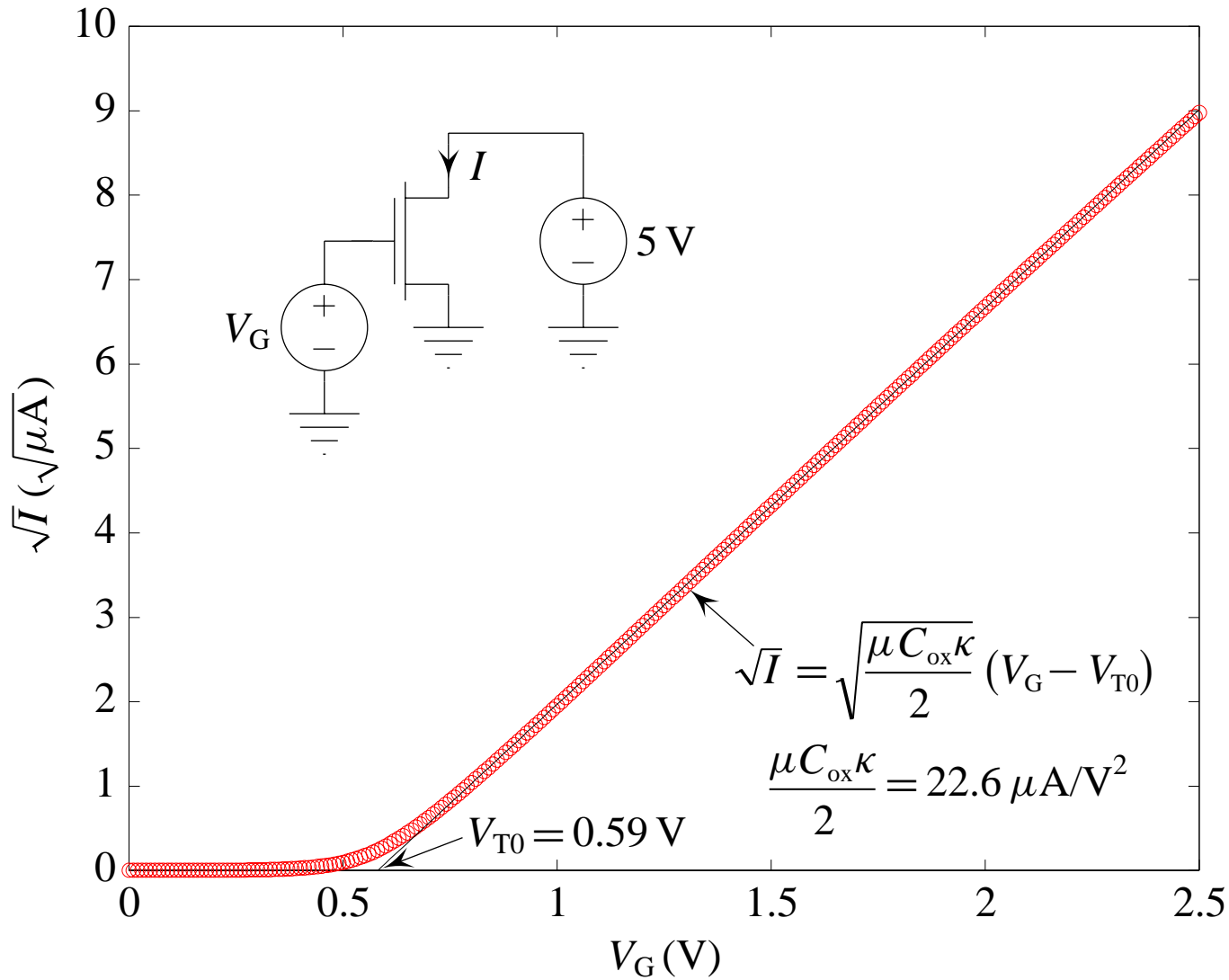
$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} \left[(\kappa((V_W - V_G) - |V_{T0}|) - (V_W - V_S))^2 - (\kappa((V_W - V_G) - |V_{T0}|) - (V_W - V_D))^2 \right]$$

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{2\kappa} (\kappa((V_W - V_G) - |V_{T0}|) - (V_W - V_S))^2, \text{ for } V_D \leq V_W - \kappa((V_W - V_G) - |V_{T0}|)$$

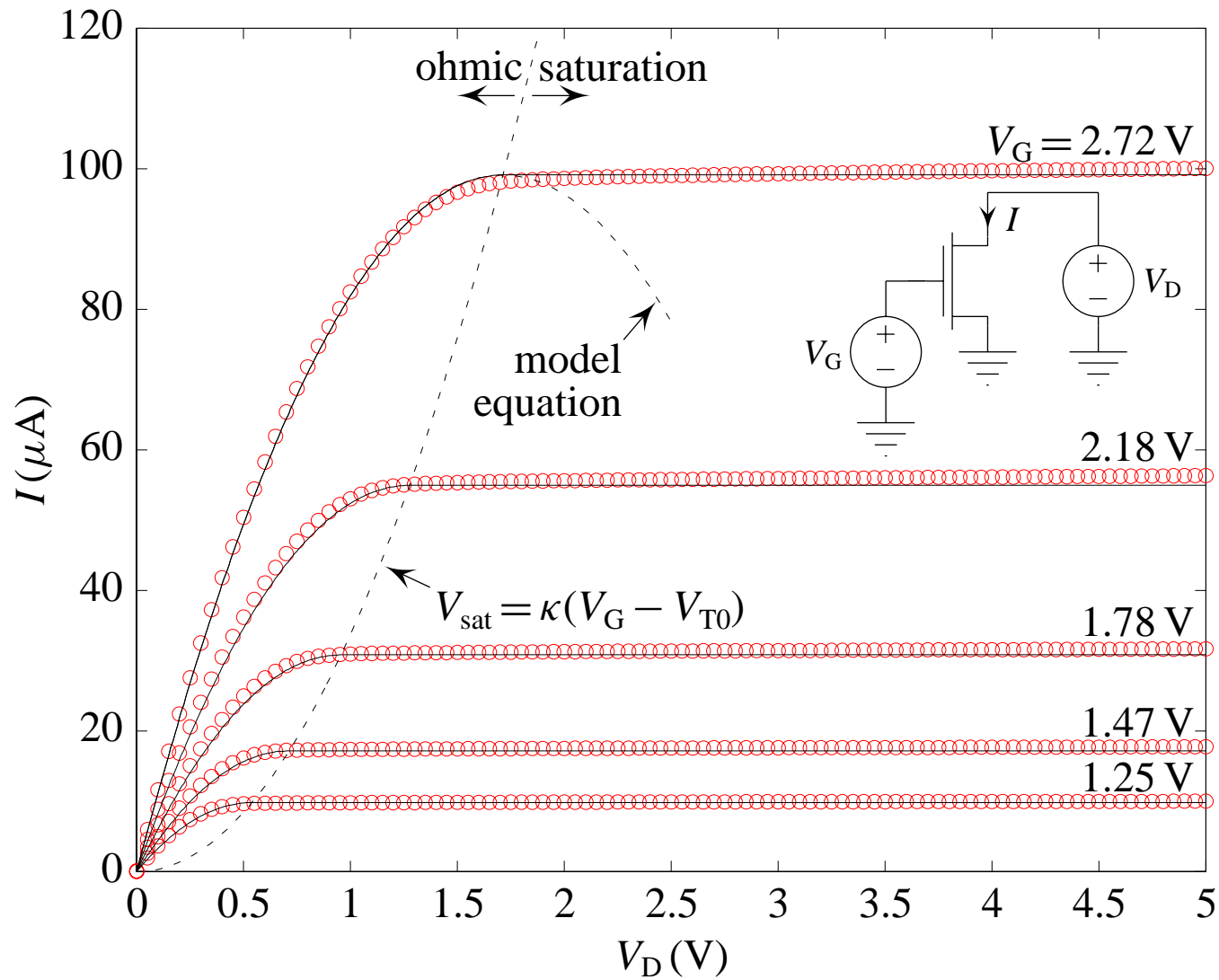


** Note here that $V_G > 0$, $V_S > 0$, $V_D > 0$, and $V_W > 0$.

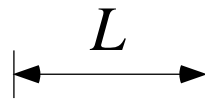
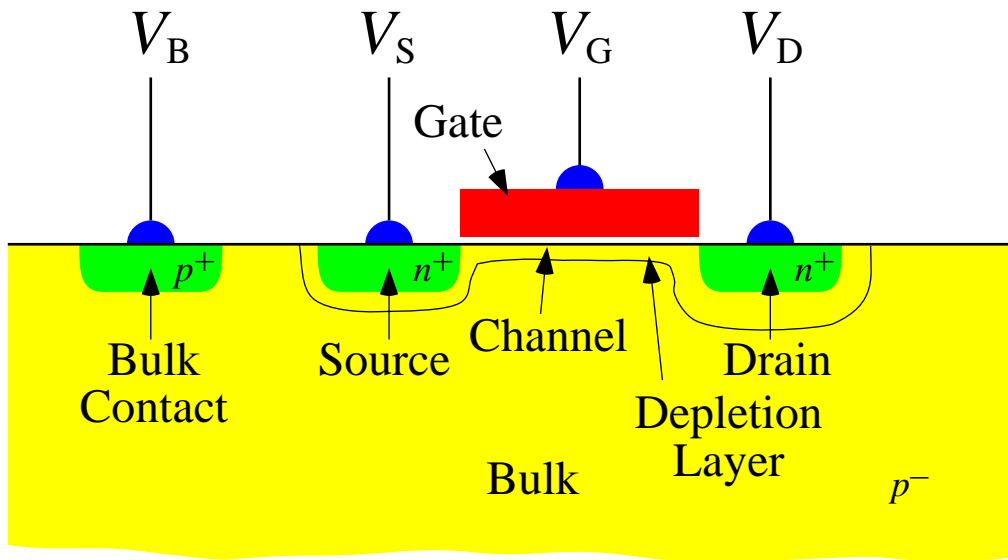
Above-Threshold Channel Current in Saturation



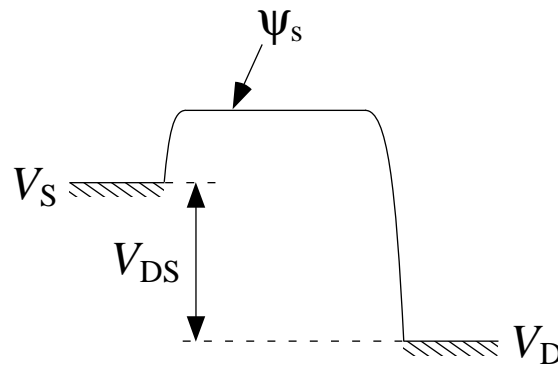
Above-Threshold Drain Characteristics



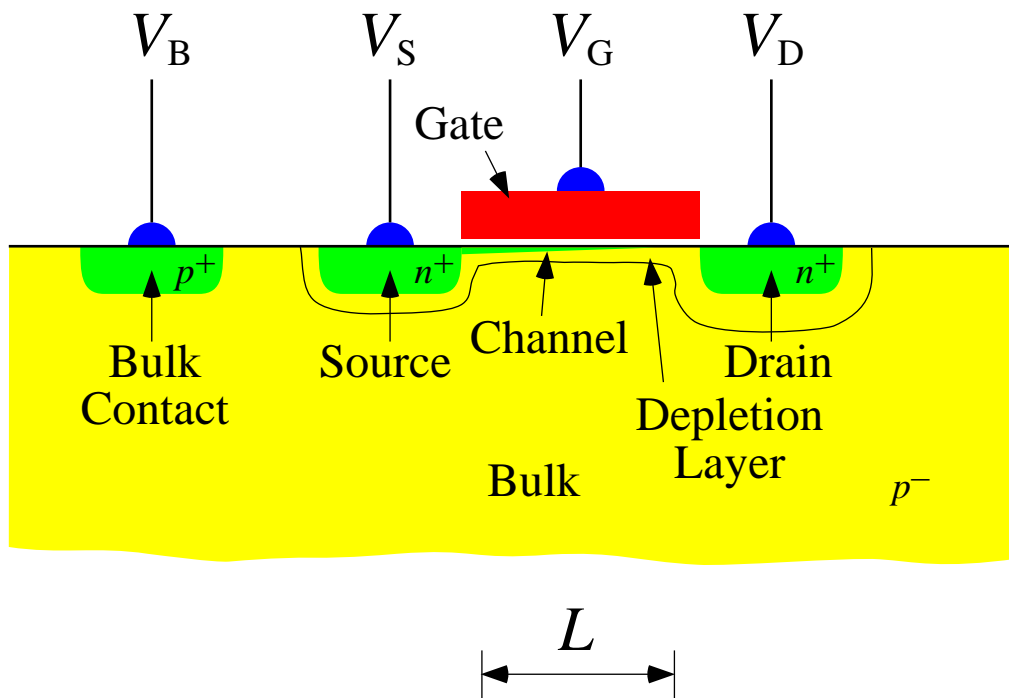
Surface Energy in Subthreshold



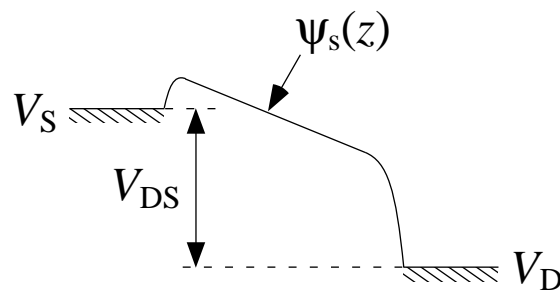
Surface Energy



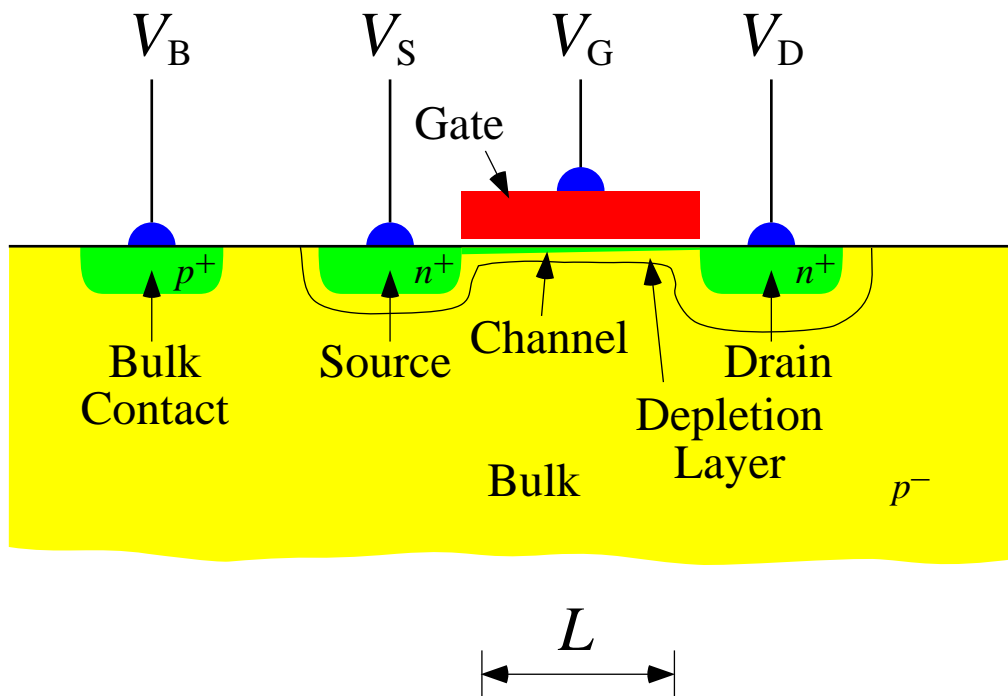
Surface Energy in Saturation Above Threshold



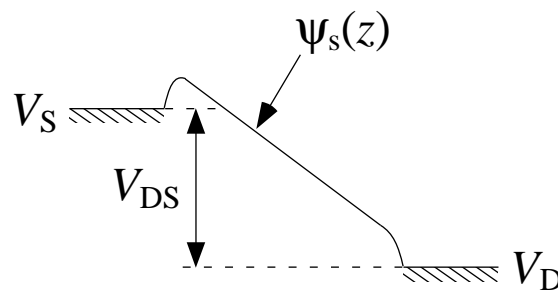
Surface Energy



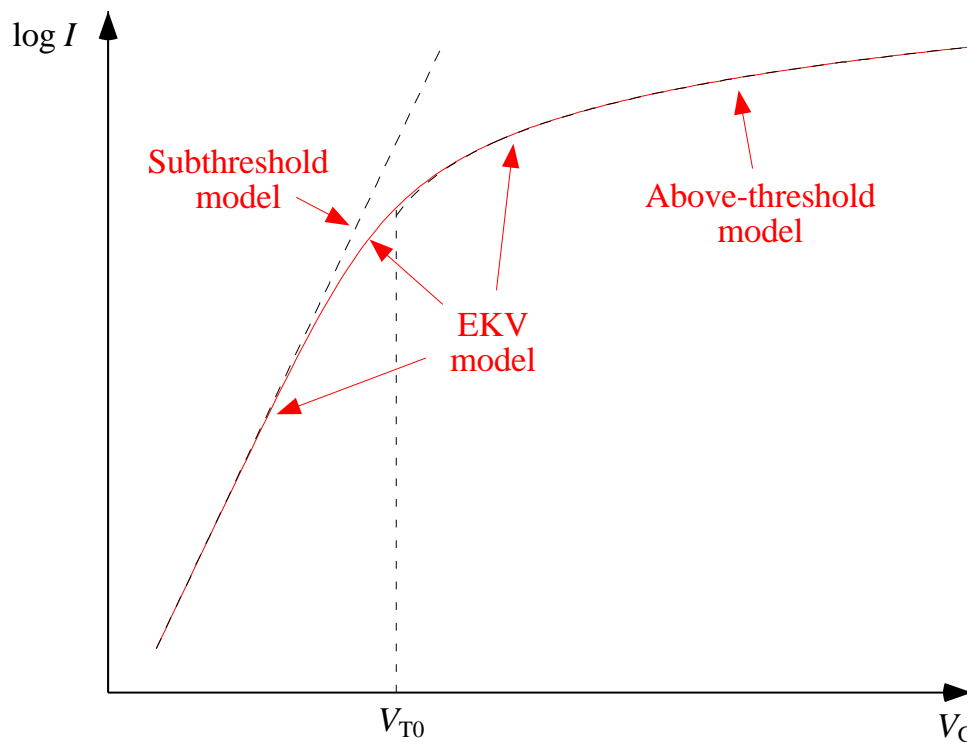
Surface Energy in Ohmic Region Above Threshold



Surface Energy



Enz-Krummenacher-Vittoz Model



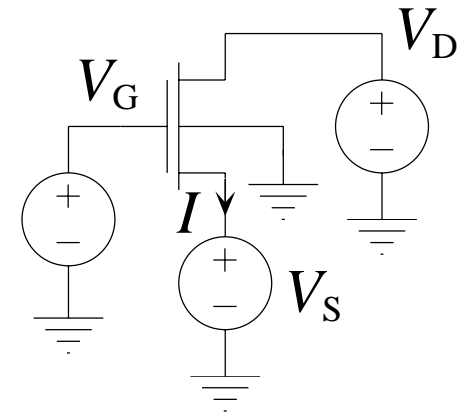
$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{\kappa} 2U_T^2 \left[\log^2 \left(1 + e^{(\kappa(V_G - V_{T0}) - V_S)/2U_T} \right) - \log^2 \left(1 + e^{(\kappa(V_G - V_{T0}) - V_D)/2U_T} \right) \right]$$

- ▶ Model is continuous from subthreshold to above threshold and is valid in both the ohmic and saturation regions.
- ▶ $\log^2(1 + e^{x/2})$ function smoothly interpolates between e^x and x^2 .
- ▶ Not based on first principles. (i.e., an elegant mathematical hack!)

EKV Model Channel Current

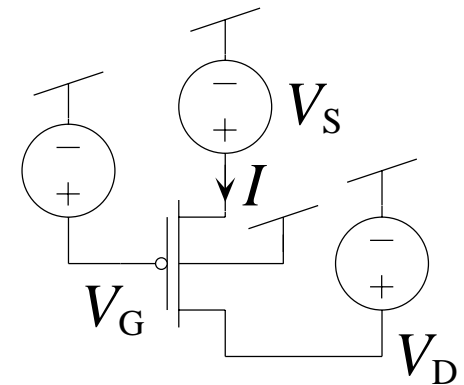
► *n*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{\kappa} 2U_{\text{T}}^2 \left[\log^2 \left(1 + e^{(\kappa(V_{\text{G}} - V_{\text{T0}}) - V_{\text{S}})/2U_{\text{T}}} \right) - \log^2 \left(1 + e^{(\kappa(V_{\text{G}} - V_{\text{T0}}) - V_{\text{D}})/2U_{\text{T}}} \right) \right]$$



► *p*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{\kappa} 2U_{\text{T}}^2 \left[\log^2 \left(1 + e^{(V_{\text{S}} - \kappa(V_{\text{G}} - V_{\text{T0}}))/2U_{\text{T}}} \right) - \log^2 \left(1 + e^{(V_{\text{D}} - \kappa(V_{\text{G}} - V_{\text{T0}}))/2U_{\text{T}}} \right) \right]$$

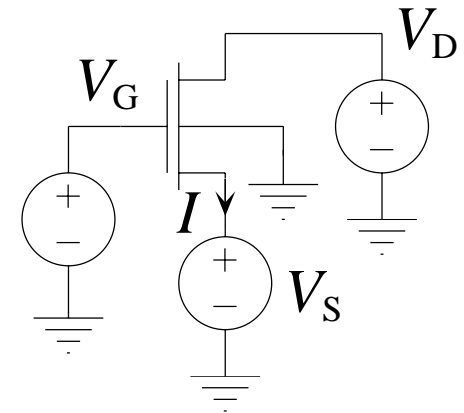


** Note here that $V_{\text{G}} < 0$, $V_{\text{S}} < 0$, $V_{\text{D}} < 0$, and $V_{\text{T0}} < 0$.

EKV Model Channel Current

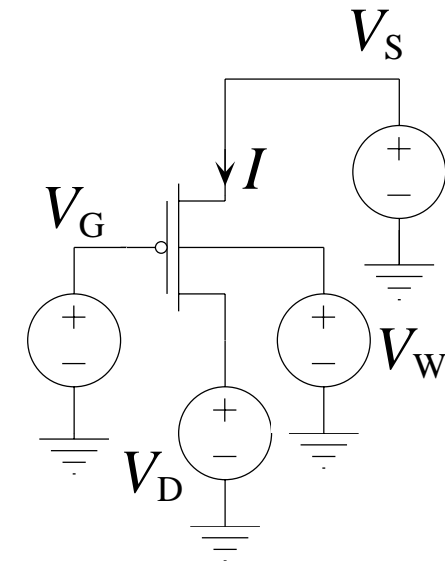
► *n*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{\kappa} 2U_{\text{T}}^2 \left[\log^2 \left(1 + e^{(\kappa(V_{\text{G}} - V_{\text{T0}}) - V_{\text{S}})/2U_{\text{T}}} \right) - \log^2 \left(1 + e^{(\kappa(V_{\text{G}} - V_{\text{T0}}) - V_{\text{D}})/2U_{\text{T}}} \right) \right]$$



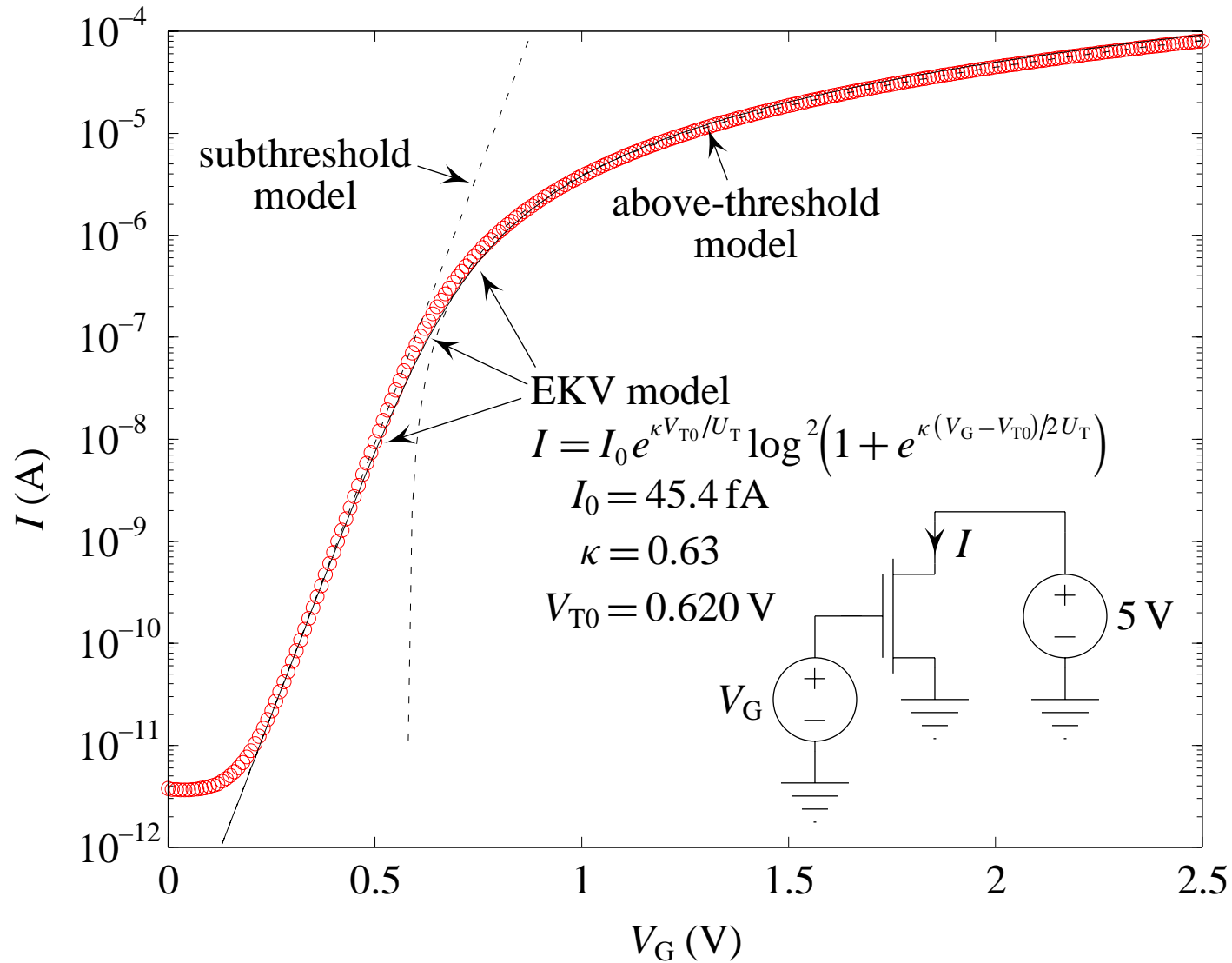
► *p*MOS:

$$I = \frac{W}{L} \frac{\mu C_{\text{ox}}}{\kappa} 2U_{\text{T}}^2 \left[\log^2 \left(1 + e^{(\kappa((V_{\text{W}} - V_{\text{G}}) - |V_{\text{T0}}|) - (V_{\text{W}} - V_{\text{S}}))/2U_{\text{T}}} \right) - \log^2 \left(1 + e^{(\kappa((V_{\text{W}} - V_{\text{G}}) - |V_{\text{T0}}|) - (V_{\text{W}} - V_{\text{D}}))/2U_{\text{T}}} \right) \right]$$

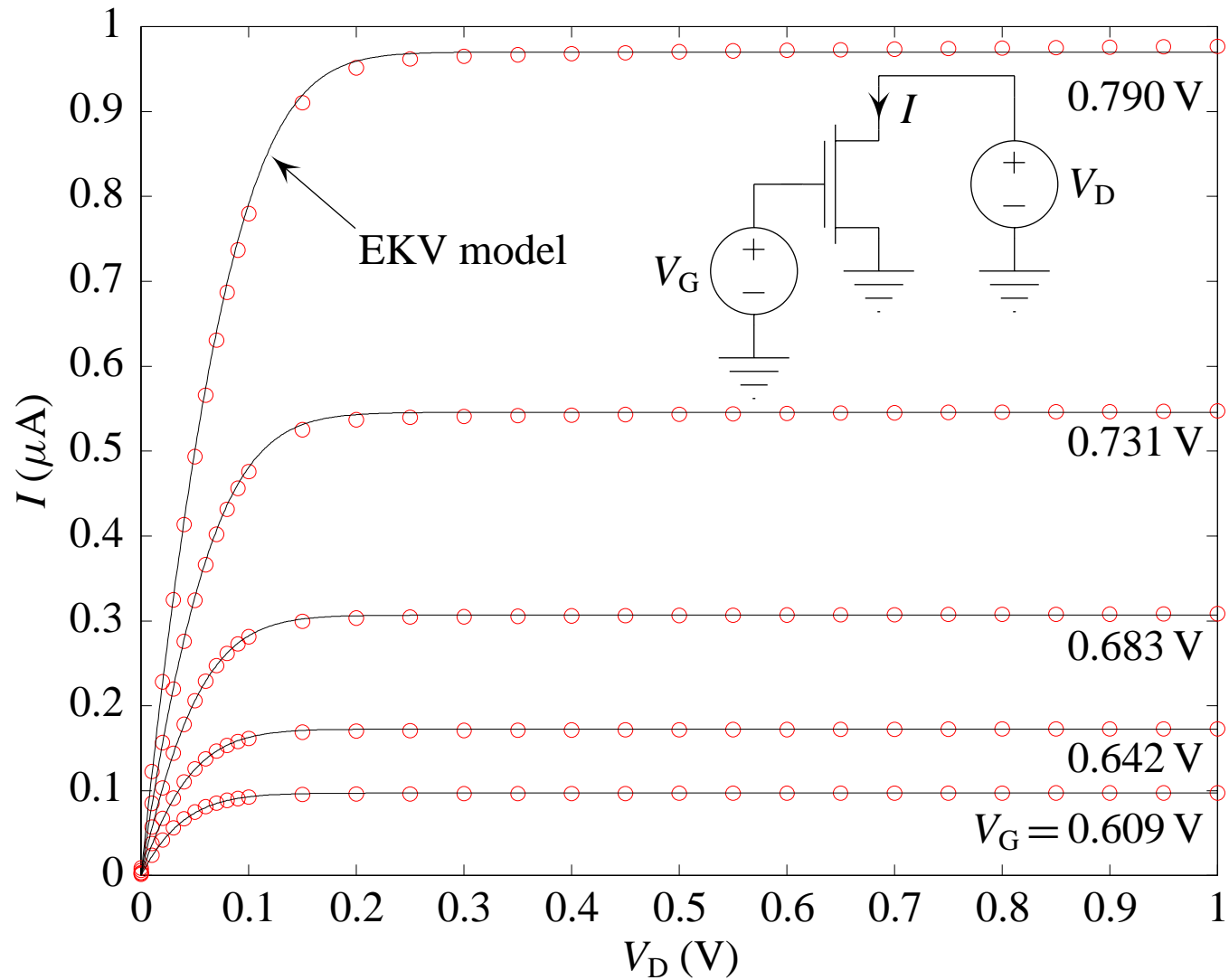


** Note here that $V_{\text{G}} > 0$, $V_{\text{S}} > 0$, $V_{\text{D}} > 0$, and $V_{\text{W}} > 0$.

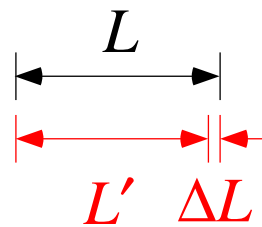
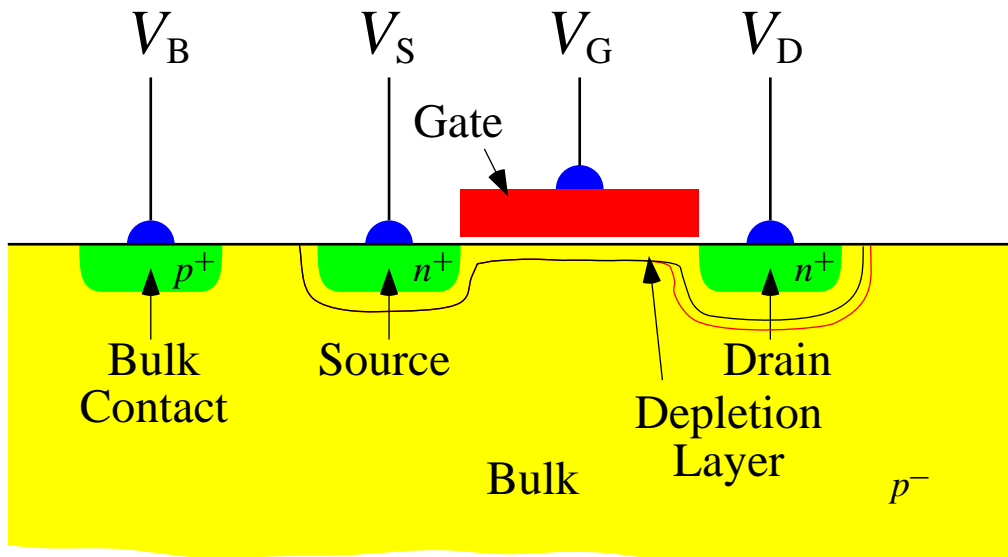
EKV Model: Channel Current in Saturation



EKV Model: Drain Characteristics



Channel Length Modulation (a.k.a. The Early Effect)



Surface Energy

